











bq27441-G1

SLUSBH1C-NOVEMBER 2013-REVISED DECEMBER 2014

# bg27441-G1 System-Side Impedance Track™ Fuel Gauge

#### **Features**

- Single Series Cell Li-Ion Battery Fuel Gauge
  - Resides on System Board
  - Supports Embedded or Removable Batteries
  - Powered Directly from Battery with Integrated
  - Supports a Low-Value External Sense Resistor  $(10 \text{ m}\Omega)$
- Battery Fuel Gauging Based on Patented Impedance Track™ Technology
  - Reports Remaining Capacity and State-of-Charge (SOC) with Smoothing Filter
  - Automatically Adjusts for Battery Aging, Selfdischarge, Temperature, and Rate Changes
  - Battery State-of-Health (Aging) Estimation
- Microcontroller Peripheral Supports:
  - 400-kHz I<sup>2</sup>C Serial Interface
  - Configurable SOC Interrupt or **Battery Low Digital Output Warning**
  - Internal Temperature Sensor or Host-Reported Temperature

# 2 Applications

- Smartphones, Feature Phones, and Tablets
- Digital Still and Video Cameras
- Handheld Terminals
- MP3 or Multimedia Players

## 3 Description

The Texas Instruments bq27441-G1 fuel gauge is a microcontroller peripheral that provides system-side fuel gauging for single-cell Li-lon batteries. The device requires minimal user configuration and system microcontroller firmware development.

The bq27441-G1 battery fuel gauge uses the patented Impedance Track™ algorithm for fuel gauging, and provides information such as remaining battery capacity (mAh), state-of-charge (%), and battery voltage (mV).

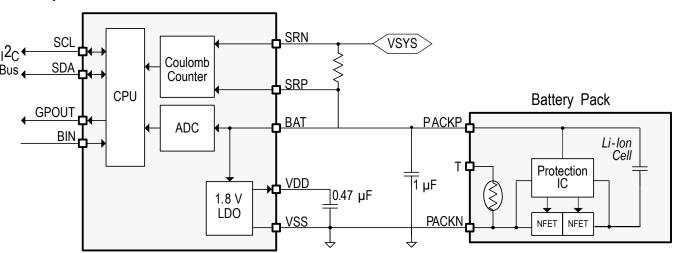
Battery fuel gauging with the bq27441-G1 fuel gauge requires connections only to PACK+ (P+) and PACK-(P-) for a removable battery pack or embedded battery circuit. The tiny, 12-pin, 2.50 mm x 4.00 mm, small outline no-lead (SON) package is ideal for space-constrained applications.

## Device Information<sup>(1)</sup>

PART NUMBER	MBER PACKAGE BODY	
bq27441-G1	VSON (12)	2.50 mm × 4.00 mm

For all available packages, see the orderable addendum at the end of the datasheet.

# **Simplified Schematic**





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### Changes from Original (November 2013) to Revision A

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# 6 Device Comparison Table

PART NUMBER	BATTERY TYPE	CHEM_ID (1)	DM_CODE (2)	FIRMWARE VERSION <sup>(3)</sup>
bq27441DRZR-G1A	LiCoO <sub>2</sub>	0x0128	0x48	
bq27441DRZT-G1A	(4.2 V maximum charge)	UXU128		1.09
bq27441DRZR-G1B	LiCoO <sub>2</sub>	0.0242	OvEQ	(0x0109)
bq27441DRZT-G1B	(4.3 to 4.35 V maximum charge)	0x0312	0x58	

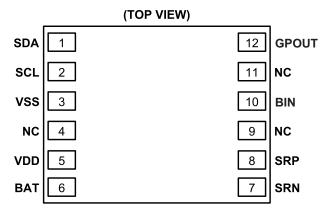
See the CHEM\_ID subcommand to confirm the battery chemistry type.

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See the *DM\_CODE* subcommand to confirm the Data Memory code. See the *FW\_VERSION* subcommand to confirm the firmware version.



# 7 Pin Configuration and Functions



## **Pin Functions**

PIN (4)		<i>(</i> 0)			
NAME	NUMBER	TYPE <sup>(1)</sup>	DESCRIPTION		
BAT	6	PI, AI	LDO regulator input and battery voltage measurement input. Kelvin sense connect to positive battery terminal (PACKP). Connect a capacitor (1 $\mu$ F) between BAT and V <sub>SS</sub> . Place the capacitor close to the gauge.		
BIN	10	DI	Battery insertion detection input. If $\textit{OpConfig} \ [\textit{Bl\_PU\_EN}\ ] = 1$ (default), a logic low on the pin is detected as battery insertion. For a removable pack, the BIN pin can be connected to $V_{SS}$ through a pulldown resistor on the pack, typically the 10-k $\Omega$ thermistor; the system board should use a 1.8-M $\Omega$ pullup resistor to $V_{DD}$ to ensure the BIN pin is high when a battery is removed. If the battery is embedded in the system, it is recommended to leave $[\textit{Bl\_PU\_EN}\ ] = 1$ and use a 10-k $\Omega$ pulldown resistor from BIN to $V_{SS}$ . If $[\textit{Bl\_PU\_EN}\ ] = 0$ , then the host must inform the gauge of battery insertion and removal with the $BAT\_INSERT$ and $BAT\_REMOVE$ subcommands. A 10-k $\Omega$ pulldown resistor should be placed between BIN and $V_{SS}$ , even if this pin is unused. NOTE: The BIN pin must not be shorted directly to $V_{CC}$ or $V_{SS}$ and any pullup resistor on the BIN pin must be connected only to $V_{DD}$ and not an external voltage rail.		
GPOUT	12	DO	This open-drain output can be configured to indicate BAT_LOW when the <i>OpConfig [BATLOWEN]</i> bit is set. By default <i>[BATLOWEN]</i> is cleared and this pin performs an interrupt function (SOC_INT) by pulsing for specific events, such as a change in state-of-charge. Signal polarity for these functions is controlled by the <i>[GPIOPOL]</i> configuration bit. This pin should not be left floating, even if unused; therefore, a 10-kΩ pullup resistor is recommended. If the device is in shutdown mode, then toggling GPOUT will make the gauge exit shutdown. Therefore, it is recommended to connect GPOUT to a GPIO of the host MCU.		
NC	4, 9, 11	_	No internal connection. May be left floating or tied to V <sub>SS</sub> .		
SCL	2	DIO	Slave I <sup>2</sup> C serial bus for communication with system (Master). Open-drain pins. Use with external		
SDA	1	DIO	10-k $\Omega$ pullup resistors (typical) for each pin. If the external pullup resistors will be disconnected from these pins during normal operation, recommend using external 1-M $\Omega$ pulldown resistors to $V_{SS}$ at each pin to avoid floating inputs.		
SRN	7	Al	Coulomb counter differential inputs expecting an external 10 mΩ, 1% sense resistor in the high-		
SRP 8 A		AI	side current path. Kelvin sense connect SRP to the positive battery terminal (PACKP) side of the external sense resistor. Kelvin sense connect SRN to the other side of the external sense resistor, the positive connection to the system (VSYS). See the <i>Simplified Schematic</i> . No calibration is required. The fuel gauge is pre-calibrated for a standard 10 mΩ, 1% sense resistor.		
V <sub>DD</sub>	5	PO	1.8-V regulator output. Decouple with 0.47- $\mu$ F ceramic capacitor to V <sub>SS</sub> . This pin is not intended to provide power for other devices in the system.		
$V_{SS}$	3	PI	Ground pin		

(1) IO = Digital input-output, AI = Analog input, P = Power connection



# 8 Specifications

## 8.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
$V_{BAT}$	BAT pin input voltage range	-0.3	6	V
V	SRP and SRN pins input voltage range	-0.3	$V_{BAT} + 0.3$	V
$V_{SR}$	Differential voltage across SRP and SRN. ABS(SRP – SRN)		2	V
$V_{DD}$	V <sub>DD</sub> pin supply voltage range (LDO output)	-0.3	2	V
$V_{IOD}$	Open-drain IO pins (SDA, SCL)	-0.3	6	V
$V_{IOPP}$	Push-pull IO pins (BIN)	-0.3	$V_{DD} + 0.3$	V
T <sub>A</sub>	Operating free-air temperature range	-40	85	°C
Storage temperature, T <sub>stg</sub>			150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 8.2 ESD Ratings

			VALUE	UNIT
	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±1500		
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±250	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

# 8.3 Recommended Operating Conditions

 $T_A = 30$ °C and  $V_{REGIN} = V_{BAT} = 3.6 \text{ V}$  (unless otherwise noted)

			MIN	TYP M	٩x	UNIT
C <sub>BAT</sub> <sup>(1)</sup>	External input capacitor for internal LDO between BAT and $\rm V_{\rm SS}$	Nominal capacitor values specified.  Recommend a 5% ceramic X5R-type capacitor located close to the device.		0.1		μF
C <sub>LDO18</sub> <sup>(1)</sup>	External output capacitor for internal LDO between $\rm V_{DD}$ and $\rm V_{SS}$			0.47		μF
V <sub>PU</sub> <sup>(1)</sup>	External pullup voltage for open-drain pins (SDA, SCL, GPOUT)		1.62	;	3.6	٧

<sup>(1)</sup> Specified by design. Not production tested.

### 8.4 Thermal Information

	THERMAL METRIC	DRZ (12 PINS)	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	64.1	
$R_{\theta JCtop}$	Junction-to-case (top) thermal resistance	59.8	
$R_{\theta JB}$	Junction-to-board thermal resistance	52.7	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	0.3	3C/W
ΨЈВ	Junction-to-board characterization parameter	28.3	
$R_{\theta JCbot}$	Junction-to-case (bottom) thermal resistance	2.4	

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



# 8.5 Supply Current

 $T_A = 30^{\circ}\text{C}$  and  $V_{\text{REGIN}} = V_{\text{BAT}} = 3.6\text{V}$  (unless otherwise noted)

	REGIT BATT					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I <sub>CC</sub> <sup>(1)</sup>	NORMAL mode current	I <sub>LOAD</sub> > <b>Sleep Current</b> <sup>(2)</sup>		93		μΑ
I <sub>SLP</sub> <sup>(1)</sup>	SLEEP mode current	I <sub>LOAD</sub> < <b>Sleep Current</b> <sup>(2)</sup>		21		μΑ
I <sub>HIB</sub> <sup>(1)</sup>	HIBERNATE mode current	I <sub>LOAD</sub> < Hibernate Current <sup>(2)</sup>		9		μΑ
I <sub>SD</sub> <sup>(1)</sup>	SHUTDOWN mode current	Fuel gauge in host commanded SHUTDOWN mode. (LDO regulator output disabled)		0.6		μΑ

<sup>(1)</sup> Specified by design. Not production tested.(2) Wake Comparator Disabled.

# 8.6 Digital Input and Output DC Characteristics

 $T_A = -40$ °C to 85°C, typical values at  $T_A = 30$ °C and  $V_{REGIN} = 3.6$  V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{IH(OD)}$	Input voltage, high (2)	External pullup resistor to V <sub>PU</sub>	V <sub>PU</sub> × 0.7			V
$V_{IH(PP)}$	Input voltage, high (3)		1.4			V
$V_{IL}$	Input voltage, low <sup>(2)</sup> (3)				0.6	V
$V_{OL}$	Output voltage, low <sup>(2)</sup>				0.6	V
I <sub>OH</sub>	Output source current, high (2)				0.5	mA
I <sub>OL(OD)</sub>	Output sink current, low(2)				-3	mA
C <sub>IN</sub> <sup>(1)</sup>	Input capacitance (2)(3)				5	pF
I <sub>lkg</sub>	Input leakage current (SCL, SDA, BIN)				0.1	μA
9	Input leakage current (GPOUT)				1	•

Specified by design. Not production tested. Open Drain pins: (SCL, SDA, GPOUT) Push-Pull pin: (BIN)



## 8.7 LDO Regulator, Wake-up, and Auto-Shutdown DC Characteristics

 $T_{\Delta} = -40^{\circ}$ C to 85°C, typical values at  $T_{\Delta} = 30^{\circ}$ C and  $V_{REGIN} = 3.6$  V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{BAT}$	BAT pin regulator input		2.45		4.5	V
$V_{DD}$	Regulator output voltage			1.8		V
UVLO <sub>IT+</sub>	V <sub>BAT</sub> undervoltage lock-out LDO wake-up rising threshold			2		V
UVLO <sub>IT</sub>	V <sub>BAT</sub> undervoltage lock-out LDO auto-shutdown falling threshold			1.95		V
V <sub>WU+</sub> <sup>(1)</sup>	GPOUT (input) LDO Wake-up rising edge threshold (2)	LDO Wake-up from SHUTDOWN mode	1.2			V

<sup>(1)</sup> Specified by design. Not production tested.

## 8.8 LDO Regulator, Wake-up, and Auto-shutdown AC Characteristics

 $T_A = -40$ °C to 85°C, typical values at  $T_A = 30$ °C and  $V_{REGIN} = 3.6$  V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>SHDN</sub> <sup>(1)</sup>	SHUTDOWN entry time	Time delay from SHUTDOWN command to LDO output disable.			250	ms
t <sub>SHUP</sub> <sup>(1)</sup>	SHUTDOWN GPOUT low time	Minimum low time of GPOUT (input) in SHUTDOWN before WAKEUP	10			μs
t <sub>VDD</sub> <sup>(1)</sup>	Initial V <sub>DD</sub> output delay			13		ms
t <sub>WUVDD</sub> <sup>(1)</sup>	Wake-up V <sub>DD</sub> output delay	Time delay from rising edge of GPOUT (input) to nominal V <sub>DD</sub> output.		8		ms
t <sub>PUCD</sub>	Power-up communication delay	Time delay from rising edge of REGIN to the Active state. Includes firmware initialization time.		250		ms

<sup>(1)</sup> Specified by design. Not production tested.

## 8.9 ADC (Temperature and Cell Measurement) Characteristics

 $T_A = -40$ °C to 85°C; typical values at  $T_A = 30$ °C and  $V_{REGIN} = 3.6$  V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>IN(BAT)</sub>	BAT pin voltage measurement range	Voltage divider enabled	2.45		4.5	V
t <sub>ADC_CONV</sub>	Conversion time			125		ms
	Effective resolution			15		bits

<sup>(1)</sup> Specified by design. Not tested in production.

# 8.10 Integrating ADC (Coulomb Counter) Characteristics

 $T_A = -40$ °C to 85°C; typical values at  $T_A = 30$ °C and  $V_{REGIN} = 3.6$  V (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{SR}$	Input voltage range from BAT to SRX pins		ı	BAT ± 25		mV
t <sub>SR_CONV</sub>	Conversion time	Single conversion		1		S
	Effective Resolution	Single conversion		16		bits

(1) Specified by design. Not tested in production.

<sup>(2)</sup> If the device is commanded to SHUTDOWN via I<sup>2</sup>C with V<sub>BAT</sub> > UVLO<sub>IT+</sub>, a wake-up rising edge trigger is required on GPOUT.



# I<sup>2</sup>C-Compatible Interface Communication Timing Characteristics

 $T_A = -40$ °C to 85°C; typical values at  $T_A = 30$ °C and  $V_{REGIN} = 3.6$  V (unless otherwise noted)

			MIN	TYP MA	X UNIT
Standard	Mode (100 kHz)		1		
t <sub>d(STA)</sub>	Start to first falling edge of SCL		4		μs
t <sub>w(L)</sub>	SCL pulse duration (low)		4.7		μs
t <sub>w(H)</sub>	SCL pulse duration (high)		4		μs
t <sub>su(STA)</sub>	Setup for repeated start		4.7		μs
t <sub>su(DAT)</sub>	Data setup time	Host drives SDA	250		ns
t <sub>h(DAT)</sub>	Data hold time	Host drives SDA	0		ns
t <sub>su(STOP)</sub>	Setup time for stop		4		μs
t <sub>(BUF)</sub>	Bus free time between stop and start	Includes Command Waiting Time	66		μs
t <sub>f</sub>	SCL or SDA fall time <sup>(1)</sup>			30	0 ns
t <sub>r</sub>	SCL or SDA rise time <sup>(1)</sup>			30	0 ns
f <sub>SCL</sub>	Clock frequency <sup>(2)</sup>			10	0 kHz
Fast Mode	e (400 kHz)				
t <sub>d(STA)</sub>	Start to first falling edge of SCL		600		ns
t <sub>w(L)</sub>	SCL pulse duration (low)		1300		ns
t <sub>w(H)</sub>	SCL pulse duration (high)		600		ns
t <sub>su(STA)</sub>	Setup for repeated start		600		ns
t <sub>su(DAT)</sub>	Data setup time	Host drives SDA	100		ns
t <sub>h(DAT)</sub>	Data hold time	Host drives SDA	0		ns
t <sub>su(STOP)</sub>	Setup time for stop		600		ns
t <sub>(BUF)</sub>	Bus free time between stop and start	Includes Command Waiting Time	66		μs
t <sub>f</sub>	SCL or SDA fall time <sup>(1)</sup>			30	0 ns
t <sub>r</sub>	SCL or SDA rise time <sup>(1)</sup>			30	0 ns
f <sub>SCL</sub>	Clock frequency (2)			40	0 kHz

- Specified by design. Not production tested. If the clock frequency ( $f_{SCL}$ ) is > 100 kHz, use 1-byte write commands for proper operation. All other transactions types are supported at 400 kHz. (See  $f_{CC}$  Interface and  $f_{CC}$  Command Waiting Time.)

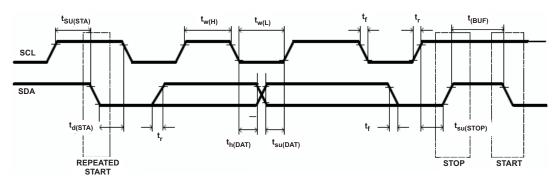
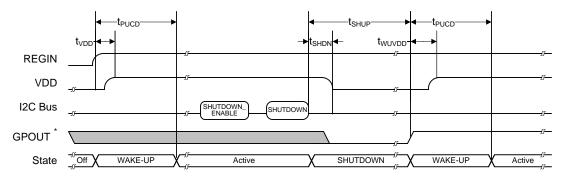


Figure 1. I<sup>2</sup>C-Compatible Interface Timing Diagrams



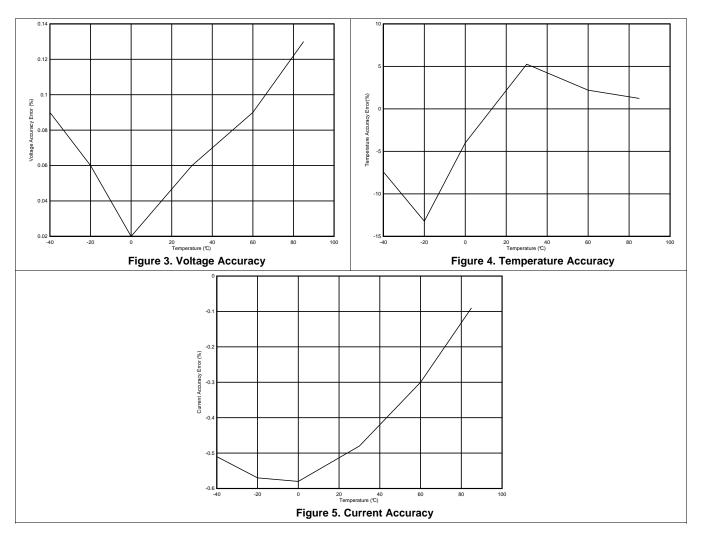
# 8.12 SHUTDOWN and WAKE-UP Timing



<sup>\*</sup> GPOUT is configured as an input for wake-up signaling.

Figure 2. SHUTDOWN and WAKE-UP Timing Diagram

# 8.13 Typical Characteristics



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### 9 Detailed Description

#### 9.1 Overview

The fuel gauge accurately predicts the battery capacity and other operational characteristics of a single Li-based rechargeable cell. It can be interrogated by a system processor to provide cell information, such as state-of-charge (SoC).

#### NOTE

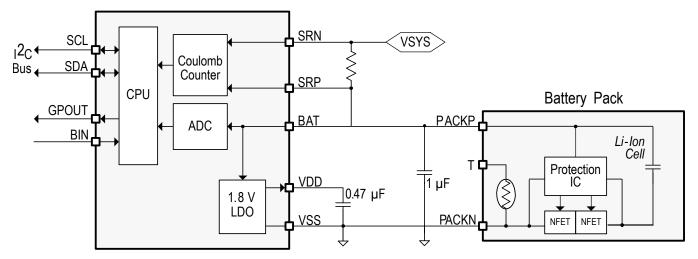
The following formatting conventions are used in this document:

Commands: italics with parentheses() and no breaking spaces, for example, Control().

Data Flash: italics, bold, and breaking spaces, for example, Design Capacity.

Register bits and flags: *italics* with brackets [], for example, *[TDA]*Data flash bits: *italics*, bold, and brackets [], for example, *[LED1]*Modes and states: ALL CAPITALS, for example, UNSEALED mode.

# 9.2 Functional Block Diagram



# 9.3 Feature Description

Information is accessed through a series of commands, called *Standard Commands*. Further capabilities are provided by the additional *Extended Commands* set. Both sets of commands, indicated by the general format *Command*), are used to read and write information contained within the control and status registers, as well as its data locations. Commands are sent from system to gauge using the I<sup>2</sup>C serial communications engine, and can be executed during application development, system manufacture, or end-equipment operation.

The key to the high-accuracy gas gauging prediction is Texas Instruments proprietary Impedance Track™ algorithm. This algorithm uses cell measurements, characteristics, and properties to create state-of-charge predictions that can achieve high accuracy across a wide variety of operating conditions and over the lifetime of the battery.

The fuel gauge measures the charging and discharging of the battery by monitoring the voltage across a small-value sense resistor. When a cell is attached to the fuel gauge, cell impedance is computed based on cell current, cell open-circuit voltage (OCV), and cell voltage under loading conditions.

The fuel gauge uses an integrated temperature sensor for estimating cell temperature. Alternatively, the host processor can provide temperature data for the fuel gauge.

More details are found in the bg27441-G1 Technical Reference Manual (SLUUAC9).



#### 9.4 Device Functional Modes

To minimize power consumption, the fuel gauge has several power modes: INITIALIZATION, NORMAL, SLEEP, and HIBERNATE. The fuel gauge passes automatically between these modes, depending upon the occurrence of specific events, though a system processor can initiate some of these modes directly. More details are found in the *bq27441-G1 Technical Reference Manual* (SLUUAC9).

### 9.5 Programming

#### 9.5.1 Standard Data Commands

The fuel gauge uses a series of 2-byte standard commands to enable system reading and writing of battery information. Each standard command has an associated command-code pair, as indicated in Table 1. Because each command consists of two bytes of data, two consecutive I<sup>2</sup>C transmissions must be executed both to initiate the command function, and to read or write the corresponding two bytes of data. Additional details are found in the *bq27441-G1 Technical Reference Manual* (SLUUAC9).

**Table 1. Standard Commands** 

NAME		COMMAND CODE	UNIT	SEALED ACCESS
Control()	CNTL	0x00 and 0x01	NA	RW
Temperature()	TEMP	0x02 and 0x03	0.1°K	RW
Voltage()	VOLT	0x04 and 0x05	mV	R
Flags()	FLAGS	0x06 and 0x07	NA	R
NominalAvailableCapacity()		0x08 and 0x09	mAh	R
FullAvailableCapacity()		0x0A and 0x0B	mAh	R
RemainingCapacity()	RM	0x0C and 0x0D	mAh	R
FullChargeCapacity()	FCC	0x0E and 0x0F	mAh	R
AverageCurrent()		0x10 and 0x11	mA	R
StandbyCurrent()		0x12 and 0x13	mA	R
MaxLoadCurrent()		0x14 and 0x15	mA	R
AveragePower()		0x18 and 0x19	mW	R
StateOfCharge()	SOC	0x1C and 0x1D	%	R
InternalTemperature()		0x1E and 0x1F	0.1°K	R
StateOfHealth()	SOH	0x20 and 0x21	num / %	R
RemainingCapacityUnfiltered()		0x28 and 0x29	mAh	R
RemainingCapacityFiltered()		0x2A and 0x2B	mAh	R
FullChargeCapacityUnfiltered()		0x2C and 0x2D	mAh	R
FullChargeCapacityFiltered()		0x2E and 0x2F	mAh	R
StateOfChargeUnfiltered()		0x30 and 0x31	%	R
TrueRemainingCapacity()		0x6A and 0x6B	mAh	R

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### 9.5.2 Control(): 0x00 and 0x01

Issuing a *Control()* command requires a subsequent 2-byte subcommand. These additional bytes specify the particular control function desired. The *Control()* command allows the system to control specific features of the fuel gauge during normal operation and additional features when the device is in different access modes, as described in Table 2. Additional details are found in the *bq27441-G1 Technical Reference Manual* (SLUUAC9).

Table 2. Control() Subcommands

CNTL FUNCTION	CNTL DATA	SEALED ACCESS	DESCRIPTION
CONTROL_STATUS	0x0000	Yes	Reports the status of device.
FW_VERSION	0x0002	Yes	Reports the firmware version of the device.
DM_CODE	0x0004	Yes	Reports the Data Memory Code number stored in NVM.
PREV_MACWRITE	0x0007	Yes	Returns previous MAC command code.
CHEM_ID	0x0008	Yes	Reports the chemical identifier of the battery profile used by the fuel gauge.
BAT_INSERT	0x000C	Yes	Forces the Flags() [BAT_DET] bit set when the OpConfig [BIE] bit is 0.
BAT_REMOVE	0x000D	Yes	Forces the Flags() [BAT_DET] bit clear when the <b>OpConfig [BIE]</b> bit is 0.
SET_HIBERNATE	0x0011	Yes	Forces CONTROL_STATUS [HIBERNATE] to 1.
CLEAR_HIBERNATE	0x0012	Yes	Forces CONTROL_STATUS [HIBERNATE] to 0.
SET_CFGUPDATE	0x0013	No	Force CONTROL_STATUS [CFGUPMODE] to 1 and gauge enters CONFIG UPDATE mode.
SHUTDOWN_ENABLE	0x001B	No	Enables device SHUTDOWN mode.
SHUTDOWN	0x001C	No	Commands the device to enter SHUTDOWN mode.
SEALED	0x0020	No	Places the device in SEALED access mode.
TOGGLE_GPOUT	0x0023	Yes	Commands the device to toggle the GPOUT pin for 1 ms.
RESET	0x0041	No	Performs a full device reset.
SOFT_RESET	0x0042	No	Gauge exits CONFIG UPDATE mode.
EXIT_CFGUPDATE	0x0043	No	Exits CONFIG UPDATE mode without an OCV measurement and without resimulating to update StateOfCharge().
EXIT_RESIM	0x0044	No	Exits CONFIG UPDATE mode without an OCV measurement and resimulates with updated configuration data to update StateOfCharge().

#### 9.5.3 Extended Data Commands

Extended data commands offer additional functionality beyond the standard set of commands. They are used in the same manner; however, unlike standard commands, extended commands are not limited to 2-byte words. The number of command bytes for a given extended command ranges in size from single to multiple bytes, as specified in Table 3.

**Table 3. Extended Commands** 

NAME	COMMAND CODE	UNIT	SEALED ACCESS <sup>(1)</sup> (2)	UNSEALED ACCESS <sup>(1)</sup> (2)
OpConfig()	0x3A and 0x3B	NA	R	R
DesignCapacity()	0x3C and 0x3D	mAh	R	R
DataClass() (2)	0x3E	NA	NA	RW
DataBlock() (2)	0x3F	NA	RW	RW
BlockData()	0x40 through 0x5F	NA	R	RW
BlockDataCheckSum()	0x60	NA	RW	RW
BlockDataControl()	0x61	NA	NA	RW
Reserved	0x62 through 0x7F	NA	R	R

<sup>(1)</sup> SEALED and UNSEALED states are entered via commands to Control() 0x00 and 0x01.

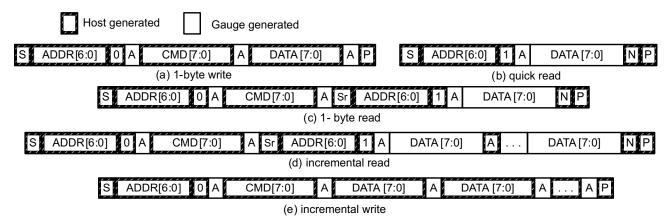
<sup>(2)</sup> In SEALED mode, data cannot be accessed through commands 0x3E and 0x3F.



#### 9.5.4 Communications

### 9.5.4.1 PC Interface

The fuel gauge supports the standard I<sup>2</sup>C read, incremental read, quick read, one-byte write, and incremental write functions. The 7-bit device address (ADDR) is the most significant 7 bits of the hex address and is fixed as 1010101. The first 8 bits of the I<sup>2</sup>C protocol are, therefore, 0xAA or 0xAB for write or read, respectively.

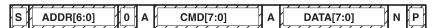


(S = Start, Sr = Repeated Start, A = Acknowledge, N = No Acknowledge, and P = Stop).

The quick read returns data at the address indicated by the address pointer. The address pointer, a register internal to the I<sup>2</sup>C communication engine, increments whenever data is acknowledged by the fuel gauge or the I<sup>2</sup>C master. "Quick writes" function in the same manner and are a convenient means of sending multiple bytes to consecutive command locations (such as two-byte commands that require two bytes of data).

The following command sequences are not supported:

Attempt to write a read-only address (NACK after data sent by master):



Attempt to read an address above 0x6B (NACK command):



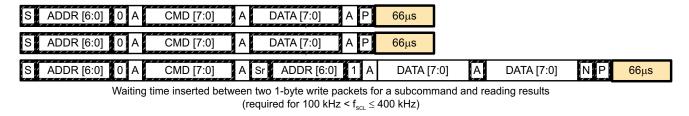
#### 9.5.4.2 PC Time Out

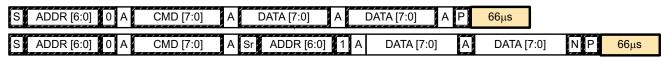
The I<sup>2</sup>C engine releases both SDA and SCL if the I<sup>2</sup>C bus is held low for 2 seconds. If the fuel gauge is holding the lines, releasing them frees them for the master to drive the lines. If an external condition is holding either of the lines low, the I<sup>2</sup>C engine enters the low-power SLEEP mode.



### 9.5.4.3 PC Command Waiting Time

To ensure proper operation at 400 kHz, a  $t_{(BUF)} \ge 66$  µs bus-free waiting time must be inserted between all packets addressed to the fuel gauge. In addition, if the SCL clock frequency ( $f_{SCL}$ ) is > 100 kHz, use individual 1-byte write commands for proper data flow control. The following diagram shows the standard waiting time required between issuing the control subcommand the reading the status result. For read-write standard command, a minimum of 2 seconds is required to get the result updated. For read-only standard commands, there is no waiting time required, but the host must not issue any standard command more than two times per second. Otherwise, the gauge could result in a reset issue due to the expiration of the watchdog timer.





Waiting time inserted between incremental 2-byte write packet for a subcommand and reading results (acceptable for  $f_{SCI} \le 100 \text{ kHz}$ )



Waiting time inserted after incremental read

### 9.5.4.4 PC Clock Stretching

A clock stretch can occur during all modes of fuel gauge operation. In SLEEP and HIBERNATE modes, a short  $\leq$  100-µs clock stretch occurs on all I<sup>2</sup>C traffic as the device must wake-up to process the packet. In the other modes (INITIALIZATION, NORMAL), a  $\leq$  4-ms clock stretching period may occur within packets addressed for the fuel gauge as the I<sup>2</sup>C interface performs normal data flow control.



## 10 Application and Implementation

#### NOTE

Information in the following application section is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 10.1 Application Information

The bg27441-G1 fuel gauge is a microcontroller peripheral that provides system-side fuel gauging for single-cell Li-lon batteries. The device requires minimal configuration and uses One Time Programmable (OTP) Non-Volatile Memory (NVM). Battery fuel gauging with the fuel gauge requires connections only to PACK+ and PACK- for a removable battery pack or embedded battery circuit. To allow for optimal performance in the end application, special considerations must be taken to ensure minimization of measurement error through proper printed circuit board (PCB) board layout. Such requirements are detailed in *Design Requirements*.

### 10.2 Typical Applications

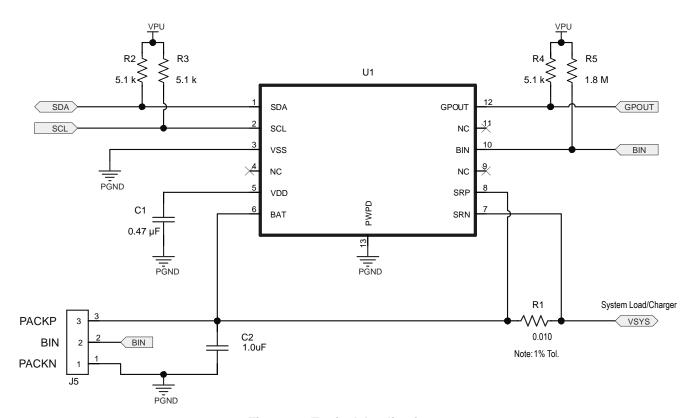


Figure 6. Typical Application

#### 10.2.1 Design Requirements

As shipped from the Texas Instruments factory, many bq27441-G1 parameters in OTP NVM are left in the unprogrammed state (zero) while some parameters directly associated with the CHEMID are preprogrammed. This partially programmed configuration facilitates customization for each end application. Upon device reset, the contents of OTP are copied to associated volatile RAM-based Data Memory blocks. For proper operation, all parameters in RAM-based Data Memory require initialization — either by updating Data Memory parameters in a lab/evaluation situation or by programming the OTP for customer production. Chapter 6 in the bq27441-G1 Technical Reference Manual (SLUUAC9) shows the default value and a typically expected value appropriate for most of applications.

Product Folder Links: bq27441-G1



## **Typical Applications (continued)**

#### 10.2.2 Detailed Design Procedure

#### 10.2.2.1 BAT Voltage Sense Input

A ceramic capacitor at the input to the BAT pin is used to bypass AC voltage ripple to ground, greatly reducing its influence on battery voltage measurements. It proves most effective in applications with load profiles that exhibit high-frequency current pulses (that is, cell phones) but is recommended for use in all applications to reduce noise on this sensitive high-impedance measurement node.

#### 10.2.2.2 Integrated LDO Capacitor

The fuel gauge has an integrated LDO with an output on the  $V_{DD}$  pin of approximately 1.8 V. A capacitor of value at least 0.47  $\mu$ F should be connected between the  $V_{DD}$  pin and  $V_{SS}$ . The capacitor should be placed close to the gauge IC and have short traces to both the  $V_{DD}$  pin and  $V_{SS}$ .

#### 10.2.2.3 Sense Resistor Selection

Any variation encountered in the resistance present between the SRP and SRN pins of the fuel gauge will affect the resulting differential voltage, and derived current, it senses. As such, it is recommended to select a sense resistor with minimal tolerance and temperature coefficient of resistance (TCR) characteristics. The standard recommendation based on best compromise between performance and price is a 1% tolerance, 50 ppm drift sense resistor with a 1-W power rating.

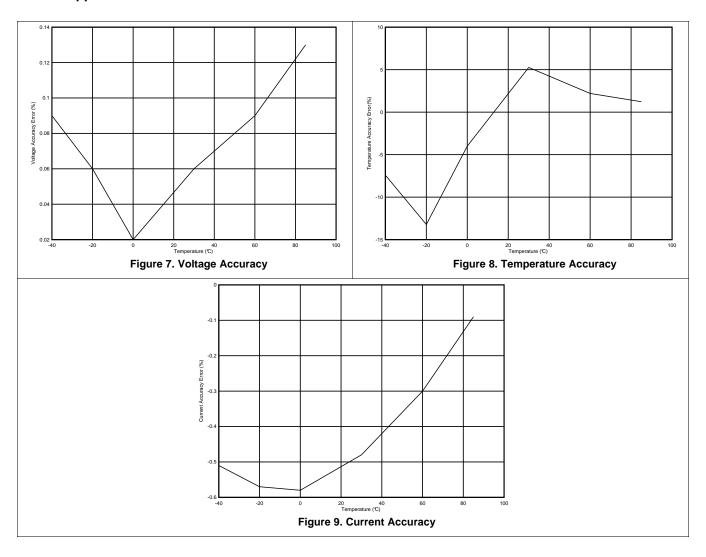
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# **Typical Applications (continued)**

# 10.2.3 Application Curves





# 11 Power Supply Recommendation

### 11.1 Power Supply Decoupling

The battery connection on the BAT pin is used for two purposes:

- · To supply power to the fuel gauge
- To provide an input for voltage measurement of the battery.

A capacitor of value of at least 1  $\mu$ F should be connected between BAT and V<sub>SS</sub>. The capacitor should be placed close to the gauge IC and have short traces to both the BAT pin and V<sub>SS</sub>.

The fuel gauge has an integrated LDO with an output on the  $V_{DD}$  pin of approximately 1.8 V. A capacitor of value at least 0.47  $\mu$ F should be connected between the  $V_{DD}$  pin and  $V_{SS}$ . The capacitor should be placed close to the gauge IC and have short traces to both the  $V_{DD}$  pin and  $V_{SS}$ .

## 12 Layout

### 12.1 Layout Guidelines

- A capacitor of a value of at least 0.47  $\mu$ F is connected between the  $V_{DD}$  pin and  $V_{SS}$ . The capacitor should be placed close to the gauge IC and have short traces to both the  $V_{DD}$  pin and  $V_{SS}$ .
- It is required to have a capacitor of at least 1.0 μF connect between the BAT pin and V<sub>SS</sub> if the connection between the battery pack and the gauge BAT pin has the potential to pick up noise. The capacitor should be placed close to the gauge IC and have short traces to both the V<sub>DD</sub> pin and V<sub>SS</sub>.
- If the external pullup resistors on the SCL and SDA lines will be disconnected from the host during low-power
  operation, it is recommend to use external 1-MΩ pulldown resistors to V<sub>SS</sub> to avoid floating inputs to the I<sup>2</sup>C
  engine.
- The value of the SCL and SDA pullup resistors should take into consideration the pullup voltage and the bus capacitance. Some recommended values, assuming a bus capacitance of 10 pF, can be seen in Table 4.

Table 4. Recommended Values for SCL and SDA Pullup Resistors

VPU	1.8 V		3.3 V				
D	Range	Typical	Range	Typical			
R <sub>PU</sub>	$400 \Omega \le R_{PU} \le 37.6 k\Omega$	10 kΩ	900 $\Omega$ ≤ R <sub>PU</sub> ≤ 29.2 k $\Omega$	5.1 kΩ			

- If the GPOUT pin is not used by the host, the pin should still be pulled up to  $V_{DD}$  with a 4.7-k $\Omega$  or 10-k $\Omega$  resistor.
- If the battery pack thermistor is not connected to the BIN pin, the BIN pin should be pulled down to V<sub>SS</sub> with a 10-kΩ resistor.
- The BIN pin should not be shorted directly to V<sub>DD</sub> or V<sub>SS</sub>.
- The actual device ground is pin 3 (V<sub>SS</sub>).
- The SRP and SRN pins should be Kelvin connected to the R<sub>SENSE</sub> terminals. SRP to the battery pack side of R<sub>SENSE</sub> and SRN to the system side of the R<sub>SENSE</sub>.
- Kelvin connect the BAT pin to the battery PACKP terminal.

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# 12.2 Layout Example

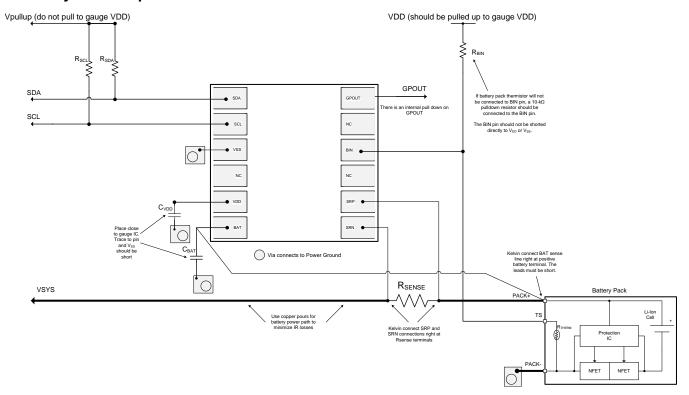


Figure 10. bq27441-G1 Board Layout

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## 13 Device and Documentation Support

### 13.1 Documentation Support

#### 13.1.1 Related Documentation

- bq27441-G1 Technical Reference Manual (SLUUAC9)
- bq27441 EVM: System-Side Impedance Track™ Technology User's Guide (SLUUAP4)
- Quickstart Guide for bg27441-G1 (SLUUAP7)
- Single Cell Gas Gauge Circuit Design (SLUA456)
- Key Design Considerations for the bg27500 and bg27501 (SLUA439)
- Single Cell Impedance Track Printed-Circuit Board Layout Guide (SLUA457)
- ESD and RF Mitigation in Handheld Battery Electronics (SLUA460)

### 13.2 Trademarks

Impedance Track is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

## 13.3 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 13.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

# 14 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

0 S





19-Dec-2014

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	_	Pins	_		Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
BQ27441DRZR-G1A	ACTIVE	SON	DRZ	12	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 441A	Samples
BQ27441DRZR-G1B	ACTIVE	SON	DRZ	12	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 441B	Samples
BQ27441DRZT-G1A	ACTIVE	SON	DRZ	12	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 441A	Samples
BQ27441DRZT-G1B	ACTIVE	SON	DRZ	12	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ27 441B	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



# **PACKAGE OPTION ADDENDUM**

19-Dec-2014

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# **PACKAGE MATERIALS INFORMATION**

www.ti.com 3-Feb-2015

# TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

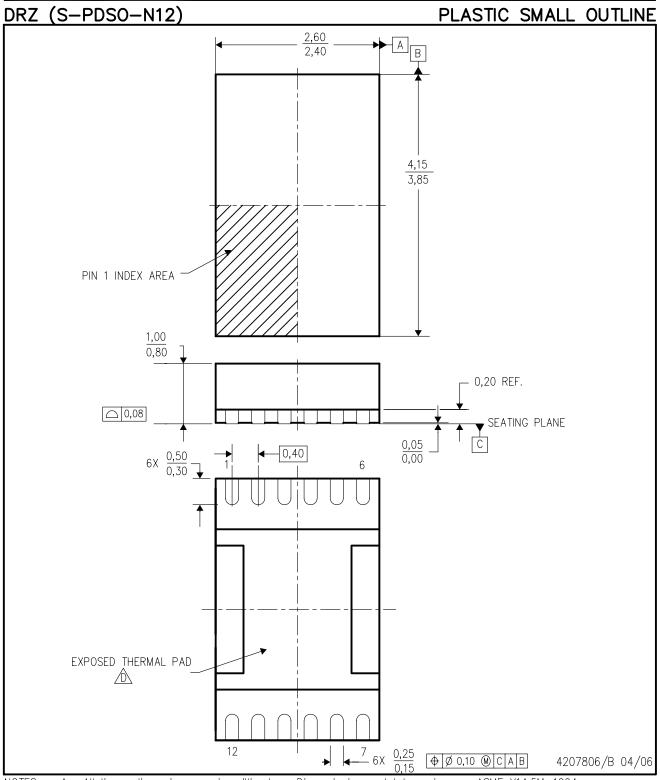
All differsions are nonlina												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ27441DRZR-G1A	SON	DRZ	12	3000	330.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2
BQ27441DRZR-G1B	SON	DRZ	12	3000	330.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2
BQ27441DRZT-G1A	SON	DRZ	12	250	180.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2
BQ27441DRZT-G1B	SON	DRZ	12	250	180.0	12.4	2.8	4.3	1.2	4.0	12.0	Q2

www.ti.com 3-Feb-2015



\*All dimensions are nominal

7 til diffictionolis are floriffial							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ27441DRZR-G1A	SON	DRZ	12	3000	367.0	367.0	35.0
BQ27441DRZR-G1B	SON	DRZ	12	3000	367.0	367.0	35.0
BQ27441DRZT-G1A	SON	DRZ	12	250	210.0	185.0	35.0
BQ27441DRZT-G1B	SON	DRZ	12	250	210.0	185.0	35.0



NOTES: All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- Small Outline No-Lead (SON) package configuration.

C. Small Outline No—Lead (SON) package configuration.

The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.

This package is lead-free.



# DRZ (R-PDSO-N12)

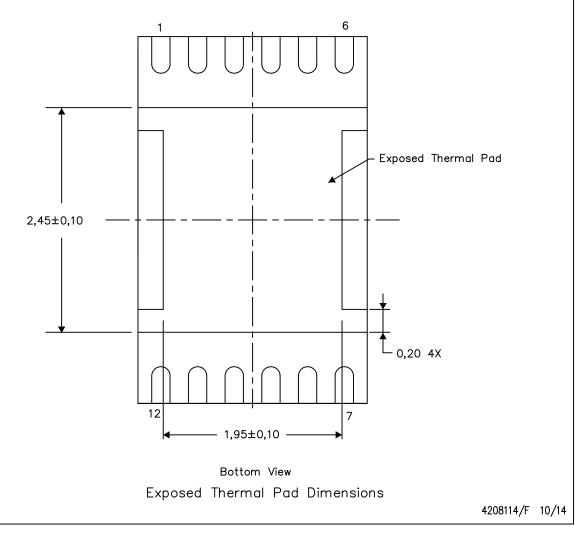
# PLASTIC SMALL OUTLINE NO-LEAD

#### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

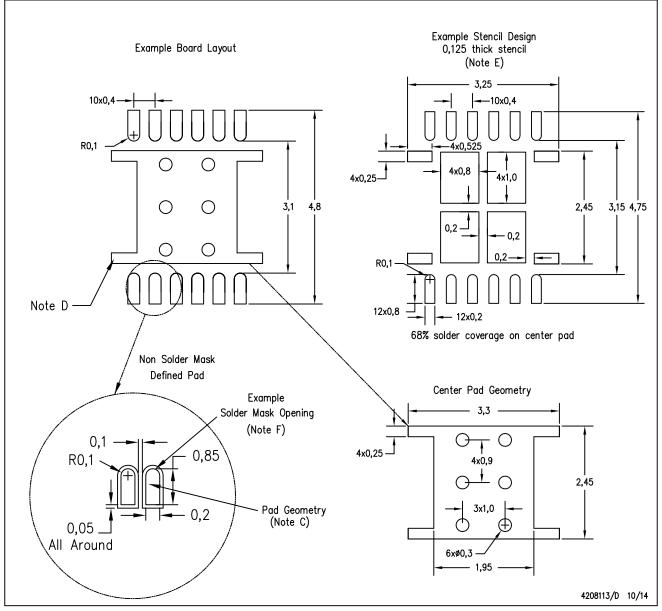


NOTE: All linear dimensions are in millimeters



# DRZ (S-PDSO-N12)

# PLASTIC SMALL OUTLINE NO-LEAD



NOTES: A.

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack Packages, Texas Instruments Literature No. SCBA017, SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <a href="http://www.ti.com">www.ti.com</a>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



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